2022년 1월 25일(화), 09:00-10:30 Room K (다이아몬드 I, 6층)

F. Silicon and Group-IV Devices and Integration Technology 분과 [TK1-F] Novel Device Characterization

좌장: 김경록 교수(UNIST), 신창환 교수(성균관대학교)

| 파 | |
|---|--|
| Self-Healing of Gate Dielectric by the Electro-Thermal Effect in MOSFETs Jun-Young Park Chungbuk National University | |
| Snapback Breakdown of MOSFETs Including Self-Heating Effects Siyoun Lee ¹ , Seong-Yeon Kim ² , Haesoon Oh ² , Jaesung Sim ² , and Woo Young Choi ¹ 1Department of Electronic Engineering, Sogang University, ² SK Hynix | |
| Temperature Dependence of SONOS Tunnel Field-Effect Transistors Jang Woo Lee, Jae Seung Woo, and Woo Young Choi Department of Electronic Engineering, Sogang University | |
| Design Optimization of Negative Capacitance Field-Effect Transistor (NCFET) with Hetero-Metal-Gate to Suppress the Reverse Drain-Induced Barrier Lowering Jae Yeon Park, Seungwon Go, Shinhee Kim, and Sangwan Kim Department of Electrical and Computer Engineering, Ajou University | |
| Experimental Observation of Negative Differential Transconductance in MOSFET + Ferroelectric Capacitor Gwon Kim, Gisu Youm, and Changhwan Shin Department of Electrical and Computer Engineering, Sungkyunkwan University | |
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